EMC TEST REPORT For

DONGGUAN KAPEGO COMPANY LIMITED

Ceiling Down Light

Model No.: B8XJ0274

Additional Model No.: B8FJ0173, B8WJ0270

Prepared for : DONGGUAN KAPEGO COMPANY LIMITED

Address : No.2 Chang Le Dong Road, YuNing Industrial Zone Heng Li

Town, Dongguan, Guangdong, China 523478

Prepared by : Shenzhen AOCE Electronic Technology Service Co., Ltd. Address : Room 202, 2nd Floor, No.12th Building of Xinhe Tongfuyu

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Guangdong, China

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Date of receipt of test sample : October 24, 2025

Number of tested samples : 1

Serial number : Prototype

Date of Test : October 24, 2025 - October 31, 2025

Date of Report : October 31, 2025



EMC TEST REPORT EN 55015: 2019+A11: 2020

Limits and methods of measurement of radio disturbance characteristics of electrical lighting and similar equipment

EN IEC 61547: 2023

Equipment for general lighting purposes - EMC immunity requirements

Report Reference No. AOC251031109E

Date Of Issue: October 31, 2025

Testing Laboratory Name.....: Shenzhen AOCE Electronic Technology Service Co., Ltd.

Room 202, 2nd Floor, No.12th Building of Xinhe Tongfuyu Address:

Industrial Park, Fuhai Street, Baoan District, Shenzhen,

Guangdong, China

Full application of Harmonised standards Testing Location/ Procedure:

Partial application of Harmonised standards

Other standard testing method

Applicant's Name: DONGGUAN KAPEGO COMPANY LIMITED

No.2 Chang Le Dong Road, YuNing Industrial Zone Heng Li Address:

Town, Dongguan, Guangdong, China 523478

Test Specification:

Standard: EN 55015:2019+A11:2020

EN IEC 61000-3-2:2019+A1:2021+A2:2024

EN 61000-3-3:2013+A1:2019+A2:2021+AC:2022

EN IEC 61547: 2023

Test Report Form No.....: AOCEMC-1.0

TRF Originator: Shenzhen AOCE Electronic Technology Service Co., Ltd.

Master TRF.....: Dated 2011-03

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Test Item Description.....: Ceiling Down Light

Trade Mark: KAPEGO

Model/ Type Reference: B8XJ0274

Ratings DC 24V, 62W, Class I, IP65

Result Positive

Compiled by:

David Lin

Supervised by:

Kevin Huang

Approved by:

Report No.: AOC251031109E

David Liu/ File administrators Kevin Huang/ Technique principal

Jackson Fang/ Manager

EMC -- TEST REPORT

Test Report No.: AOC251031109E

October 31, 2025

Date of issue

Type / Model	: Ceiling Down Light
EUT	: B8XJ0274
Applicant	: DONGGUAN KAPEGO COMPANY LIMITED
Address	: No.2 Chang Le Dong Road, YuNing Industrial Zone Heng Li Town, Dongguan, Guangdong, China 523478
Telephone	: /
Fax	: /
Manufacturer	: DONGGUAN KAPEGO COMPANY LIMITED
Address	: No.2 Chang Le Dong Road, YuNing Industrial Zone Heng Li
	Town, Dongguan, Guangdong, China 523478
Telephone	: /
Fax	: /
Factory	: DONGGUAN KAPEGO COMPANY LIMITED
Address	: No.2 Chang Le Dong Road, YuNing Industrial Zone Heng Li
	Town, Dongguan, Guangdong, China 523478
Telephone	: /
Fax	: /

Test Result according to the standards on page 6: Pass

The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

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1. SUMMARY OF STANDARDS AND RESULTS

1.1.Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below.

EN	AISS	SION (EN 55015: 2019+A11: 2020)				
Description of Test Item		Standard		Limits	Results	
Conducted disturbance at mains terminals		EN 55015: 2019+A11: 2020			N/A	
Magnetic field emission		EN 55015: 2019+A11: 2020			PASS	
Radiated disturbance		EN 55015: 2019+A11: 2020			PASS	
Harmonic current emissions	El	N IEC 61000-3-2: 2019+A1:2021+A2:202	24	Class C	N/A	
Voltage fluctuations & flicker	Voltage fluctuations & flicker EN 61000-3-3:2013+A1:2019+A2:2021+AC:2022					
IMMUNITY (EN IEC 61547: 2023)						
Description of Test Item		Basic Standard		formance riteria	Results	
Electrostatic discharge (ESD)		EN 61000-4-2: 2009		В	PASS	
Radio-frequency, Continuous radiated disturbance		EN 61000-4-3: 2020		A	PASS	
Electrical fast transient (EFT)		EN 61000-4-4: 2012		В	N/A	
Surge (Input a.c. power ports)		EN 61000-4-5: 2014+A1: 2017		В	N/A	
Radio-frequency, Continuous conducted disturbance		EN 61000-4-6: 2014+AC: 2015		A	N/A	
Power frequency magnetic field	ld EN 61000-4-8: 2010		A	PASS		
Voltage dips, 30% reduction		EN 61000-4-11: 2020		С	N/A	
Voltage interruptions		EN 01000-4-11; 2020	_	В	N/A	
N/A is an abbreviation for Not Appl	icabl	le.				

1.2.Description of Performance Criteria

General Performance Criteria

Examples of functions defined by the manufacturer to be evaluated during testing include, but are not limited to, the following:

- essential operational modes and states;
- tests of all peripheral access (hard disks, floppy disks, printers, keyboard, mouse, etc.);
- quality of software execution;
- quality of data display and transmission;
- quality of speech transmission.

1.2.1.Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be deriver from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

1.2.2.Performance criterion B

After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacture, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operation state or stored data is allowed to persist after the test.

If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be deriver from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

1.2.3.Performance criterion C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacture's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be loss.

2. GENERAL INFORMATION

2.1.Description of Device (EUT)

EUT : Ceiling Down Light

Model Number : B8XJ0274

Power Supply : DC 24V, 62W, Class I, IP65

2.2.Description of Test Facility

EMC Lab.

2.3. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. To CISPR 16 – 4 "Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements" and is documented in the AOC quality system acc. To DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

2.4. Measurement Uncertainty

Test Item	Frequency Range	Uncertainty	Note
Dediction Uncertainty	30MHz~200MHz	±2.96dB	(1)
Radiation Uncertainty:	200MHz~1000MHz	±3.10dB	(1)
Conduction Uncertainty :	150kHz~30MHz	±1.63dB	(1)
Power disturbance	30MHz~300MHz	±1.60dB	(1)

(1). This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3. MEASURING DEVICES AND TEST EQUIPMENT

3.1.Conducted Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2025/04/13
2	10dB Attenuator	SCHWARZBECK	OSPAM236	9729	2025/04/13
3	Artificial Mains	ROHDE & SCHWARZ	ENV216	101288	2025/04/13
4	EMI Test Software	AUDIX	E3	N/A	2025/04/13

3.2.Disturbance Power

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2025/04/13
2	Absorbing clamp	ROHDE & SCHWARZ	MDS 21	4033	2025/04/13
3	EMI Test Software	AUDIX	E3	N/A	2025/04/13

3.3.Radiated Electromagnetic Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	1011423	2025/04/13
2	Triple-loop Antenna	EVERFINE	LLA-2	11050003	2025/04/13
3	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2025/04/13
4	EMI Test Software	AUDIX	E3	N/A	2025/04/13

3.4. Radiated Disturbance (Electric Field)

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	3m Semi Anechoic Chamber	SIDT FRANKONIA	SAC-3M	03CH03-HY	2025/04/13
2	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2025/04/13
3	Log per Antenna	SCHWARZBECK	VULB9163	9163-470	2025/04/13
4	EMI Test Software	AUDIX	E3	N/A	2025/04/13
5	Positioning Controller	MF	MF-7082	/	2025/04/13

3.5. Harmonic Current

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power Analyzer Test System	Voltech	PM6000	20000670053	2025/04/13

3.6. Voltage fluctuation and Flicker

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power Analyzer Test System	Voltech	PM6000	20000670053	2025/04/13

3.7. Electrostatic Discharge

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	ESD Simulator	KIKUSUI	KC001311	KES4021	2025/04/13

3.8.RF Field Strength Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	SIGNAL GENERATOR	HP	8648A	625U00573	2025/04/13
2	Amplifier	AR	500A100	17034	2025/04/13
3	Amplifier	AR	100W/1000M1	17028	2025/04/13
4	Isotropic Field Monitor	AR	FM2000	16829	2025/04/13
5	Isotropic Field Probe	AR	FP2000	16755	2025/04/13
6	Bi-conic Antenna	EMCO	3108	9507-2534	2025/04/13
7	By-log-periodic Antenna	AR	AT1080	16812	2025/04/13
8	EMS Test Software	ROHDE & SCHWARZ	ESK1	N/A	2025/04/13

3.9. Electrical Fast Transient/Burst

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Electrical fast transient(EFT)generator	3CTEST	EFT-4021	EC0461044	2025/04/13
2	Coupling Clamp	3CTEST	EFTC	EC0441098	2025/04/13

3.10.Surge

Item	Test Equipment	Test Equipment Manufacturer Model No.		Serial No.	Last Cal.
1	Surge test system	3CTEST	SG5006G	EC5581070	2025/04/13
2	Coupling/decoupling network	3CTEST	SGN-5010G	CS5591033	2025/04/13

3.11.Conducted Susceptibility

Item	Test Equipment Manufacturer Model No.		Serial No.	Last Cal.	
1	Simulator	Simulator EMTEST CIT		A126A1195	2025/04/13
2	CDN	EMTEST	CDN-M2	A2210177	2025/04/13
3	CDN	EMTEST	CDN-M3	A2210177	2025/04/13
4	Attenuator	EMTEST	ATT6	50FP-006-H3B	2025/04/13

3.12. Power Frequency Magnetic Field Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power frequency mag-field generator System	EVERFINE	EMS61000-8K	906003	2025/04/13

3.13. Voltage Dips

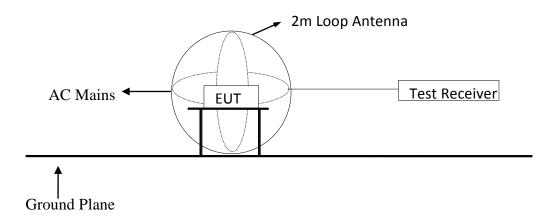
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Voltage dips and up generator	3CTEST	VDG-1105G	EC0171014	2025/04/13

3.14. Voltage Short Interruptions

Item	Test Equipment	Test Equipment Manufacturer Model No.		Serial No.	Last Cal.
1	Voltage dips and up generator	3CTEST	VDG-1105G	EC0171014	2025/04/13

4. MAGNETIC FIELD EMISSION MEASUREMENT

4.1.Block Diagram of Test Setup



4.2. Magnetic Field Emission Measurement Standard and Limits

4.2.1.Test Standard

EN 55015: 2019+A11: 2020

4.2.2.Test Limits

Frequency	Limits for loop diameter (dBµA)
Trequency	2m
9kHz ~ 70kHz	88
70kHz ~ 150kHz	88 ~ 58*
150kHz ~ 3.0MHz	58 ~ 22*
3.0MHz ~ 30MHz	22

- 1. At the transition frequency the lower limit applies.
- 2. * decreasing linearly with logarithm of the frequency.

4.3.EUT Configuration on Test

The configuration of the EUT is same as Section 3.3.

4.4. Operating Condition of EUT

- 4.4.1. Setup the EUT as shown in Section 4.1.
- 4.4.2. Turn on the power of all equipments.
- 4.4.3.Let the EUT work in test mode (On) and measure it.

4.5.Test Procedure

The EUT is placed on a wood table in the center of a loop antenna. The induced current in the loop antenna is measured by means of a current probe and the test receiver. Three field components are checked by means of a coaxial switch.

The frequency range from 9kHz to 30MHz is investigated. The receiver is measured with the quasi-peak detector. For frequency band 9kHz to 150kHz, the bandwidth of the field strength meter is set at 200Hz. For frequency band 150kHz to 30MHz, the bandwidth is set at 9kHz.

All the test results are listed in Section 4.6.

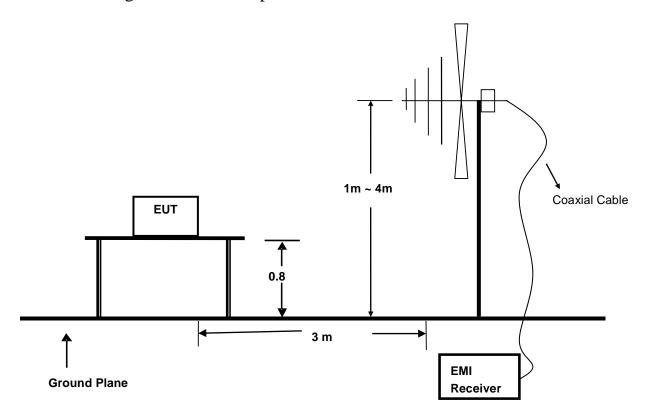
4.6.Test Results

PASS.

The frequency range from 9kHz to 30MHz is investigated.

5. RADIATED EMISSION MEASUREMENT

5.1.Block Diagram of Test Setup



5.2.Test Standard

EN 55015: 2019+A11: 2020

5.3. Radiated Emission Limits

All emanations from a class B device or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified below:

FREQUENCY	DISTANCE	FIELD STRENGTHS LIMIT
(MHz)	(Meters)	$(dB\mu V/m)$
30 ~ 230	3	40
230 ~ 300	3	47

Note: (1) The smaller limit shall apply at the combination point between two frequency bands.

(2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT.

5.4.EUT Configuration on Test

The EN 55015 regulations test method must be used to find the maximum emission during radiated emission measurement.

5.5. Operating Condition of EUT

- 5.5.1 Turn on the power.
- 5.5.2 After that, let the EUT work in test mode (ON) and measure it.

5.6.Test Procedure

The EUT is placed on a turntable, which is 0.8 meter high above the ground. The turntable can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 10 meters away from the receiving antenna, which is mounted on an antenna tower. The antenna can be moved up and down from 1 to 4 meters to find out the maximum emission level. By-log antenna (calibrated by Dipole Antenna) is used as a receiving antenna. Both horizontal and vertical polarization of the antenna is set on test.

The bandwidth of the Receiver is set at 120kHz.

The frequency range from 30MHz to 300MHz is investigated.

5.7.Test Results

PASS.

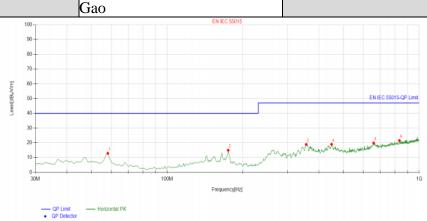
The test result please refer to the next page.

Model No.	B8XJ0274	Test Mode	ON
Environmental Conditions	24℃/ 56% RH	Detector Function	Quasi-peak
Pol	Vertical	Distance	3m
Test Engineer	Gao		



Suspe	Suspected List											
NO.	Freq. [MHz]	Factor [dB]	Reading [dBµV/m]	Level [dBµV/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity			
1	36.796797	-17.35	40.20	22.85	40.00	17.15	100	212	Vertical			
2	47.477477	-17.23	41.40	24.17	40.00	15.83	100	0	Vertical			
3	58.158158	-18.07	45.85	27.78	40.00	12.22	100	110	Vertical			
4	68.838839	-19.53	36.61	17.08	40.00	22.92	100	257	Vertical			
5	153.31331	-17.03	36.27	19.24	40.00	20.76	100	247	Vertical			
6	356.24624	-15.92	30.92	15.00	47.00	32.00	100	28	Vertical			

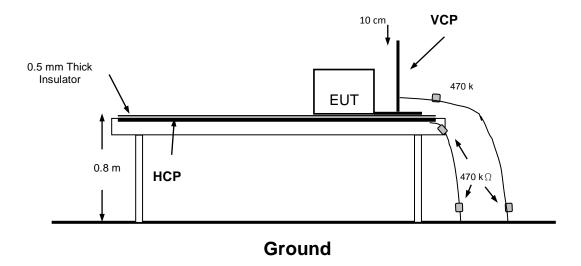
Model No.B8XJ0274Test ModeONEnvironmental Conditions24°C/56% RHDetector FunctionQuasi-peakPolHorizontalDistance3mTest EngineerGao



Suspe	Suspected List											
NO.	Freq. [MHz]	Factor [dB]	Reading [dBµV/m]	Level [dBµV/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity			
1	58.158158	-18.07	30.97	12.90	40.00	27.10	100	217	Horizontal			
2	174.67467	-18.06	33.05	14.99	40.00	25.01	100	358	Horizontal			
3	356.24624	-15.92	34.86	18.94	47.00	28.06	100	234	Horizontal			
4	449.45945	-14.12	33.12	19.00	47.00	28.00	100	138	Horizontal			
5	660.16016	-9.70	29.58	19.88	47.00	27.12	100	253	Horizontal			
6	834.93493	-7.29	28.85	21.56	47.00	25.44	100	151	Horizontal			

6. ELECTROSTATIC DISCHARGE TEST

6.1.Block Diagram of Test Setup



6.2.Test Standard

EN IEC 61547: 2023 (EN 61000-4-2: 2009, Severity Level: Air Discharge: Level 3, ±8KV

Contact Discharge: Level 2, ±4KV)

6.3. Severity Levels and Performance Criterion

6.3.1.Severity level

Level	Test Voltage	Test Voltage
	Contact Discharge (KV)	Air Discharge (KV)
1.	±2	±2
2.	±4	±4
3.	±6	±8
4.	±8	±15
X	Special	Special

6.3.2.Performance criterion: **B**

6.4.EUT Configuration on Test

The configuration of EUT is listed in Section 3.7.

6.5. Operating Condition of EUT

- 6.5.1. Setup the EUT as shown in Section 6.1.
- 6.5.2. Turn on the power of all equipments.
- 6.5.3.Let the EUT work in test mode (ON) and measure it.

6.6.Test Procedure

6.6.1.Air Discharge

This test is done on a non-conductive surfaces. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Because the case of the EUT is metal surface, so it does not need to be tested.

6.6.2.Contact Discharge

All the procedure shall be same as Section 6.6.1. except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

6.6.3.Indirect Discharge For Horizontal Coupling Plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1m from the EUT and with the discharge electrode touching the coupling plane.

6.6.4.Indirect Discharge For Vertical Coupling Plane

At least 20 single discharge shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

6.7. Test Results

PASS.

Please refer to the following page.

В

Standard

Applicant

Criterion

EUT

M/N

Electronic Technology Service Co., Ltd.		I	Report No.: AUC251031109E		
F	Electrostatic Discharger Test Results				
	☐ IEC 61000-4-2 ☑ EN 61000-4-2				
	Sonway Co.,Limited				
	Ceiling Down Light	Temperature	26℃		
	B8XJ0274	Humidity	51%		

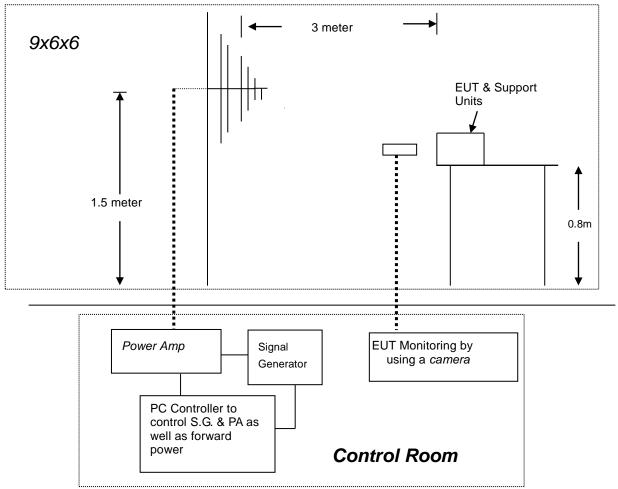
1021mbar

Pressure

Test Mode	ON			Test E	ngineer	Gao
		A	ir Discharge)		
		Test Levels			Re	esults
Test Points	± 2KV	± 4KV	± 8KV	Pass	Fail	Performance Criterion
Front	\boxtimes	\boxtimes	\boxtimes	\square		\Box A \boxtimes B
Back		\boxtimes	\boxtimes	\boxtimes		\Box A \boxtimes B
Left		\boxtimes		\boxtimes		\Box A \boxtimes B
Right	\boxtimes	\boxtimes	\boxtimes	\boxtimes		\Box A \boxtimes B
Тор		\boxtimes		\boxtimes		\Box A \boxtimes B
Bottom		\boxtimes		\boxtimes		\Box A \boxtimes B
		Con	tact Dischar	rge		
		Test Levels			Re	esults
Test Points	± 2 KV		±4 KV	Pass	Fail	Performance Criterion
Front			\boxtimes	\boxtimes		\Box A \boxtimes B
Back			\boxtimes	\boxtimes		\Box A \boxtimes B
Left			\boxtimes	\boxtimes		\Box A \boxtimes B
Right			\boxtimes	\boxtimes		\Box A \boxtimes B
Тор			\boxtimes	\boxtimes		\Box A \boxtimes B
Bottom			\boxtimes	\boxtimes		$\Box \mathbf{A} \boxtimes \mathbf{B}$
	Disc	harge To H	Iorizontal C	oupling Pla	ne	
		Test Levels				esults
Side of EUT	± 2 KV		± 4 KV	Pass	Fail	Performance Criterion
Front			\boxtimes	\boxtimes		\Box A \boxtimes B
Back			\boxtimes	\boxtimes		\Box A \boxtimes B
Left			\boxtimes	\boxtimes		\Box A \boxtimes B
Right			\boxtimes	\boxtimes		\Box A \boxtimes B
	Discharge To Vertical Coupling Plane					
		Test Levels			Re	esults
Side of EUT	± 2 KV		± 4 KV	Pass	Fa	il Performance Criterion
Front			\boxtimes	\boxtimes		\Box A \boxtimes B
Back			\boxtimes	\boxtimes		\Box A \boxtimes B
Left			\boxtimes	\boxtimes		\Box A \boxtimes B
Right			\boxtimes	\boxtimes		\Box A \boxtimes B

7. RF FIELD STRENGTH SUSCEPTIBILITY TEST

7.1.Block Diagram of Test Setup



7.2.Test Standard

EN IEC 61547: 2023 (EN 61000-4-3: 2020, Severity Level: 2, 3V / m)

7.3. Severity Levels and Performance Criterion

7.3.1.Severity level

Level	Field Strength (V/m)
1	1
2	3
3	10
X	Special

7.3.2.Performance criterion: A

7.4.EUT Configuration on Test

The configuration of EUT are listed in Section 2.1.

7.5. Operating Condition of EUT

- 7.5.1. Setup the EUT as shown in Section 7.1.
- 7.5.2. Turn on the power of all equipments.
- 7.5.3.Let the EUT work in test mode (On) and measure it.

7.6.Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above ground. EUT is set 3 meter away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarization of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually. In order to judge the EUT performance, a CCD camera is used to monitor EUT screen. All the scanning conditions are as follows:

Condition of Test		Remarks		
1.	Fielded Strength	3 V/m (Severity Level 2)		
2.	Radiated Signal	Unmodulated		
3.	Scanning Frequency	80 - 1000 MHz		
4.	Dwell time of radiated	0.0015 decade/s		
5.	Waiting Time	3 Sec.		

7.7.Test Results

PASS.

Please refer to the following page.

RF Field Strength Susceptibility Test Results					
Standard	☐ IEC 61000-4-3 ☐ EN 61000-4	☐ IEC 61000-4-3			
Applicant	Sonway Co.,Limited				
EUT	Ceiling Down Light	Temperature	26℃		
M/N	B8XJ0274	Humidity	51%		
Field Strength	3 V/m	Criterion	A		
Test Mode	ON	Test Engineer	Gao		
Frequency Range	80 MHz to 1000 MHz				
Modulation	□None □ Pulse	☑AM 1KHz 80%			
Steps	1%				

	Horizontal	Vertical
Front	PASS	PASS
Right	PASS	PASS
Rear	PASS	PASS
Left	PASS	PASS

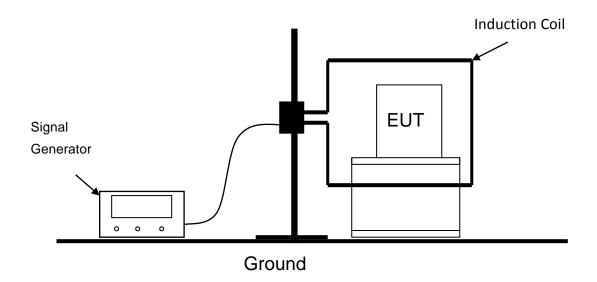
Test Equipment:

- 1. Signal Generator: 2031 (MARCONI)
- 2. Power Amplifier: 500A100 & 100W/1000M1 (A&R)
- 3. Power Antenna: 3108 (EMCO) & AT1080 (A&R)
- 4. Field Monitor: FM2000 (A&R)

Note:

8. MAGNETIC FIELD IMMUNITY TEST

8.1.Block Diagram of Test Setup



8.2.Test Standard

EN IEC 61547: 2023 (EN 61000-4-8: 2010, Severity Level 2: 3A/m)

8.3. Severity Levels and Performance Criterion

8.3.1.Severity level

develley level	
Level	Magnetic Field Strength (A/m)
1.	1
2.	3
3.	10
4.	30
5.	100
X	Special

8.3.2.Performance criterion: A

8.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.12.

8.5. Operating Condition of EUT

- 8.5.1. Setup the EUT as shown in Section 8.1.
- 8.5.2. Turn on the power of all equipments.
- 8.5.3.Let the EUT work in test mode (On) and measure it.

8.6.Test Procedure

- 8.6.1.Set up the EUT system as shown on Section 8.1.
- 8.6.2. The Induction coil is set up in horizontal or vertical.
- 8.6.3.Let the EUT work in test mode and measure it.

8.7.Test Results

PASS.

Please refer to the following page.

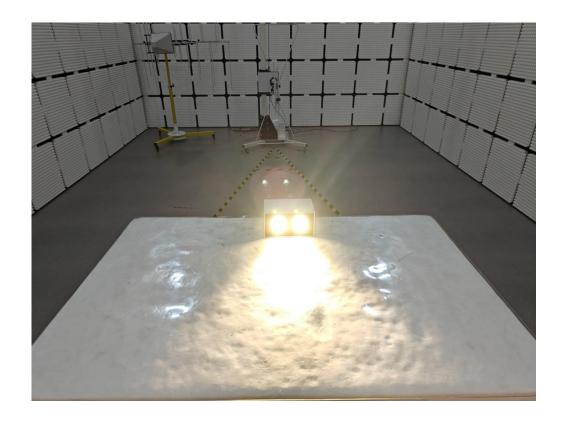
Magnetic Field Immunity Test Result			
Standard	☐ IEC 61000-4-8 ☐ EN 61000-4-8		
Applicant	Sonway Co.,Limited		
EUT	Ceiling Down Light	Temperature	26℃
M/N	B8XJ0274	Humidity	51%
Test Mode	ON	Criterion	A
Test Engineer	Gao		

Test Level (A/M)	Testing Duration	Coil Orientation	Criterion	Result
3	5 mins	X	A	PASS
3	5 mins	Y	A	PASS
3	5 mins	Z	A	PASS

Note:

9. PHOTOGRAPH

9.1.Photo of Radiated Measurement



9. EXTERNAL AND INTERNAL PHOTOS OF THE EUT

B8XJ0274 PHOTOS

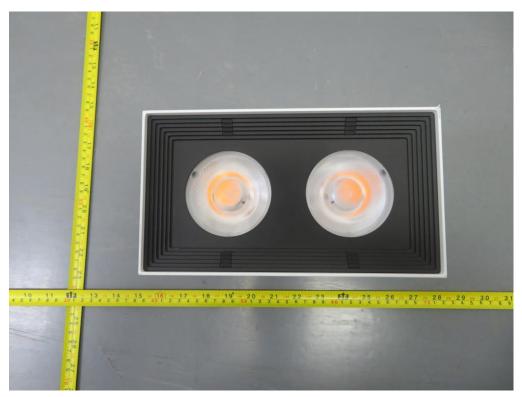


Fig. 1

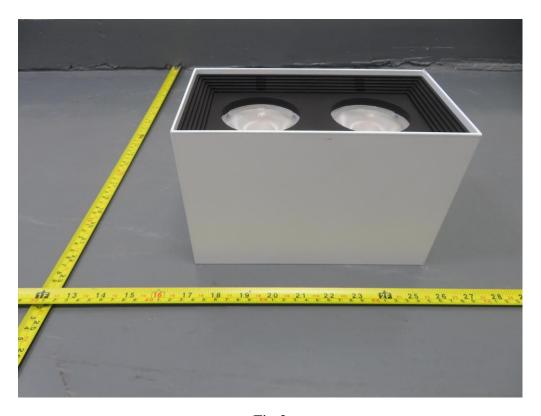


Fig.2

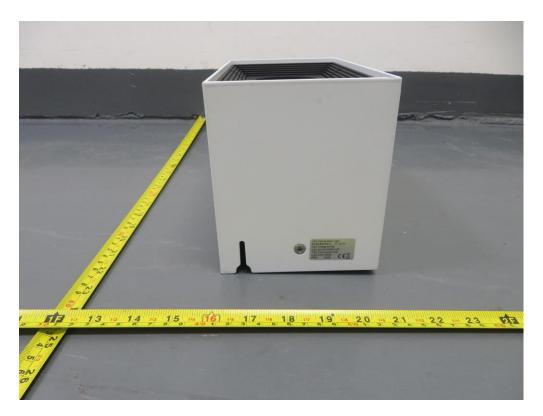


Fig.3

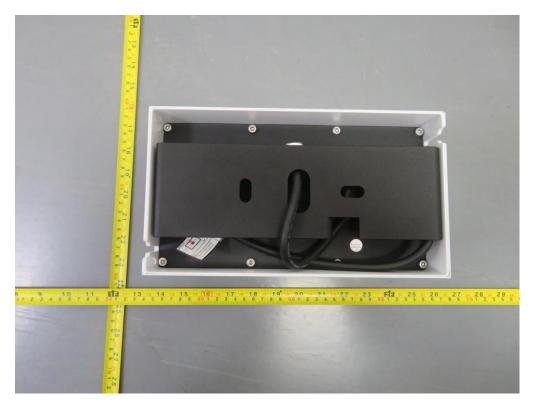


Fig.4

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